Basic Information :

Name :	Mohamed Hassan Elmahlawy
Title :	Associate Professor

Associate Professor of Electronics, Faculty of Engineering & Technology, Future University in Egypt
Design for testability of electronic circuits

Education:

Certificate	Major	University	Year
PhD	Electrical Engineering - Electronics	University of Kent- Faculty Of Engineering - Canterbury - United Kingdom	2002
Masters	Electrical Engineering	Military Technical College	1995
Bachelor	Electrical Engineering	Military Technical College	1989

Teaching Experience:

Name Of Organization	Position	From Date	To Date
FUE	Associate Professor	04/09/2016	Current

Researches / Publications :

Normalized signature graph of analog circuits for fault classification using digital testing

New Board-Level Interconnect Fault Diagnosis Approach in Industrial Applications

Hybrid Segmentation Approach for Digital Circuits in Pseudo-Exhaustive Testing

Digital Testing for Parametric Fault Detection in Analog Circuits Using Classified Frequency-Bands and Efficient Test-Point

Brain Tumor Image Segmentation Based on Deep Residual Networks (ResNets)

New Digital Testing of Analogue Circuits Based on Frequency Band Classification

Remote Fault Diagnosis for Testing Digital Circuits through Internet of Things in Industrial Applications

Remote Fault Diagnosis for Testing Digital Circuits through Internet of Things in Industrial Applications

New Hybrid-Based Self-Test Strategy for Faulty Modules of Complex Microcontroller Systems

Efficient Microcontroller System to Test an SRAM Chip Using Signature Analysis

Test Pattern Generator Optimization for Digital Testing of Analogue Circuits

Efficient Computerized-Tomography Reconstruction Using Low-Cost FPGA-DSP Chip

Digital Signature Based Test of Analogue Circuits Using Amplitude Modulated Multi-Tone Signals

Two-Test Pattern Capabilities of the LFSR/SR Generator in Pseudo-Exhaustive Testing based on Coding Theory Principles

New Algorithm to Segment Combinational Circuits in Pseudo-Exhaustive Testing

Signature-Based Self-Test Approach for Single-Shot Circuits on the Circuit Board Level

New Testability Analysis and Multi-Frequency Test Set Compaction Method for Analogue Circuits

New Test Pattern Generators for the BIST Pseudo-Exhaustive Testing based on Coding Theory Principles

FPGA-Based Implementation of the Digital Testing of Analogue Circuits

Signature Multi-Mode Hardware-Based Self-Test Architecture for Digital Integrated Circuits

Design and Development of a Low Cost Prosthetic Arm Control System Based On sEMG Signal

Low-Power Low-Noise CTIA Readout Integrated Circuit Design for Thermal Imaging Applications

Monitoring of Upper-Limb EMG Signal Activities Using a Low Cost System: Towards a Power-Assist Robotic Arm

Monitoring of Upper-Limb EMG Signal Activities Using a Low Cost System; Towards a Power-Assist Robotic Arm

New Digital Testing of Analogue Circuits

Parametric Fault Detection of Analogue Circuits

Hybrid based Self-Test Solution for Embedded System on Chip

Normalized signature graph of analog circuits for fault classification using digital testing

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